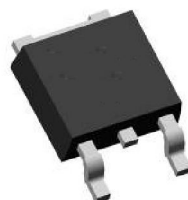
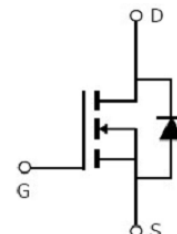


## Main Product Characteristics

$V_{DSS}$	650V
$R_{DS(on)}$	0.65Ω (typ.)
$I_D$	7A <sup>①</sup>



TO-252 (DPAK)



Schematic Diagram

## Features and Benefits

- High dv/dt and avalanche capabilities
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance



## Description

The SSF7NS65UD utilizes the latest processing techniques to achieve high cell density, low on-resistance and high repetitive avalanche rating. These features make this device extremely efficient and reliable for use in power switching applications and a wide variety of other applications.

## Absolute Maximum Ratings

Symbol	Parameter	Max.	Units
$I_D @ T_C = 25^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	7 <sup>①</sup>	A
$I_D @ T_C = 100^\circ\text{C}$	Continuous Drain Current, $V_{GS} @ 10\text{V}$	5 <sup>①</sup>	
$I_{DM}$	Pulsed Drain Current <sup>②</sup>	28	
$P_D @ T_C = 25^\circ\text{C}$	Power Dissipation <sup>③</sup>	42	W
	Linear Derating Factor	0.33	W/°C
$V_{DS}$	Drain-Source Voltage	650	V
$V_{GS}$	Gate-to-Source Voltage	± 30	V
$E_{AS}$	Single Pulse Avalanche Energy @ L=100mH	480	mJ
$I_{AS}$	Avalanche Current @ L=100mH	3.1	A
$T_J, T_{STG}$	Operating Junction and Storage Temperature Range	-55 to +150	°C

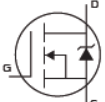
## Thermal Resistance

Symbol	Characteristics	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case <sup>③</sup>	—	3.0	°C/W
$R_{\theta JA}$	Junction-to-Ambient ( $t \leq 10\text{s}$ ) <sup>④</sup>	—	62	°C/W

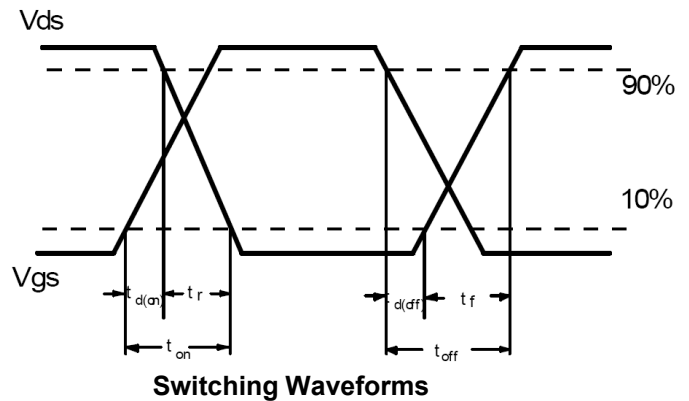
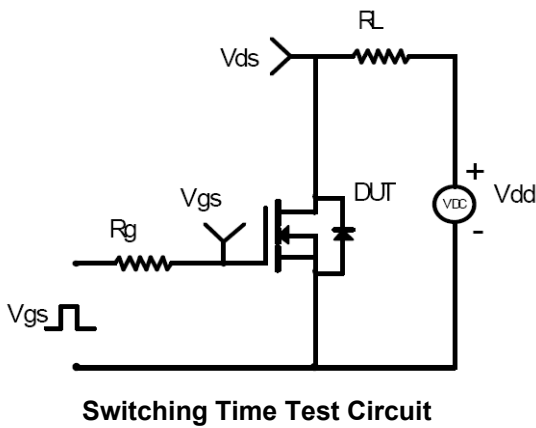
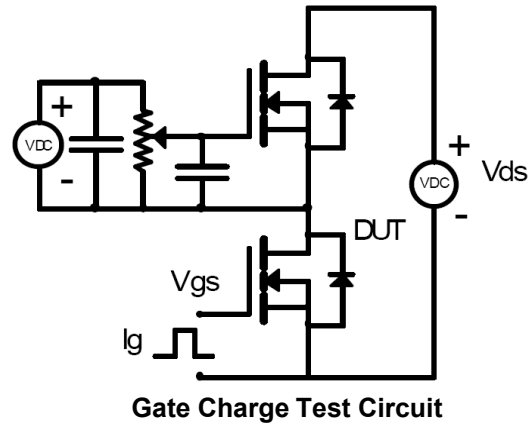
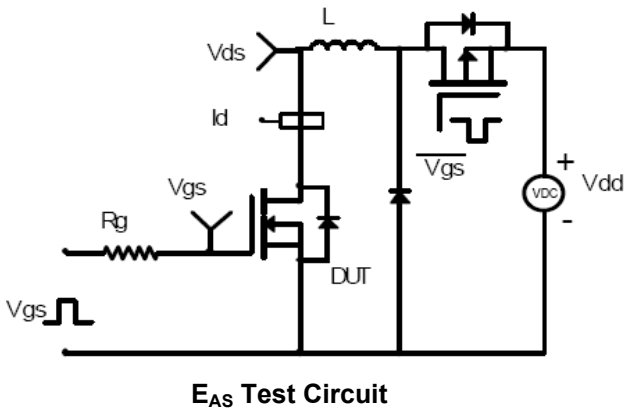
**Electrical Characteristics** ( $T_A=25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	650	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$R_{DS(on)}$	Static Drain-to-Source On-resistance	—	0.65	0.75	$\Omega$	$V_{GS}=10V, I_D = 1A$ $T_J = 125^\circ\text{C}$
		—	1.38	—		
		—	0.77	0.85	$\Omega$	$V_{GS}=10V, I_D = 4.8A$ $T_J = 125^\circ\text{C}$
		—	2.0	—		
$V_{GS(th)}$	Gate Threshold Voltage	2	—	4	V	$V_{DS} = V_{GS}, I_D = 250\mu A$ $T_J = 125^\circ\text{C}$
		—	2.2	—		
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	1	$\mu A$	$V_{DS} = 650V, V_{GS} = 0V$ $T_J = 125^\circ\text{C}$
		—	—	50		
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 30V$ $V_{GS} = -30V$
		—	—	-100		
$Q_g$	Total Gate Charge	—	13	—	nC	$I_D = 5A,$ $V_{DS}=200V,$ $V_{GS} = 10V$
$Q_{gs}$	Gate-to-Source Charge	—	2.6	—		
$Q_{gd}$	Gate-to-Drain("Miller") Charge	—	3.1	—		
$t_{d(on)}$	Turn-on Delay Time	—	9.6	—	ns	$V_{GS}=10V, V_{DS} = 400V,$ $R_{GEN}=10.2\Omega, I_D = 2.2A$
$t_r$	Rise Time	—	6	—		
$t_{d(off)}$	Turn-Off Delay Time	—	26	—		
$t_f$	Fall Time	—	10	—		
$C_{iss}$	Input Capacitance	—	500	—	pF	$V_{GS} = 0V$ $V_{DS} = 100V$ $f = 1MHz$
$C_{oss}$	Output Capacitance	—	24	—		
$C_{rss}$	Reverse Transfer Capacitance	—	3	—		

**Source-Drain Ratings and Characteristics**

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$I_S$	Continuous Source Current (Body Diode)	—	—	7 ①	A	MOSFET symbol showing the integral reverse p-n junction diode. 
$I_{SM}$	Pulsed Source Current (Body Diode)	—	—	28	A	
$V_{SD}$	Diode Forward Voltage	—	0.85	1.2	V	$I_S=4.8A, V_{GS}=0V$
$t_{rr}$	Reverse Recovery Time	—	111	—	nS	$T_J = 25^\circ\text{C}, I_F = 2.2A,$
$Q_{rr}$	Reverse Recovery Charge	—	639	—	nC	$di/dt = 100A/\mu s$

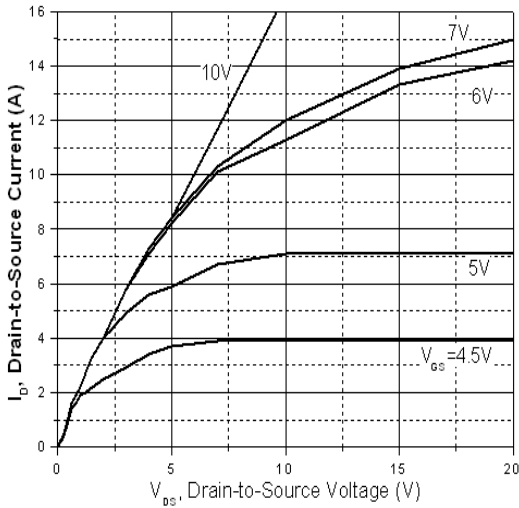
**Test Circuits and Waveforms**



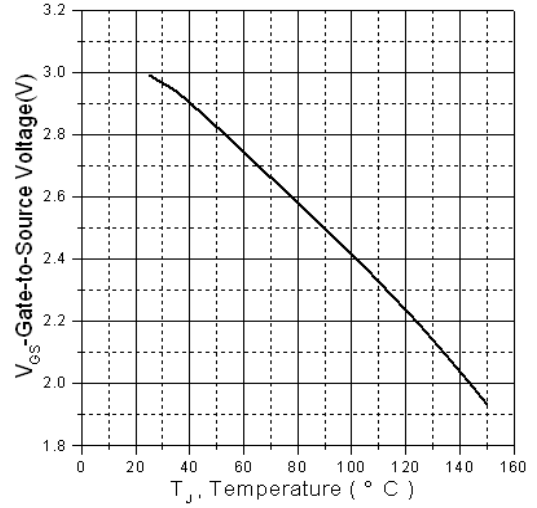
**Notes**

- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation  $P_D$  is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$

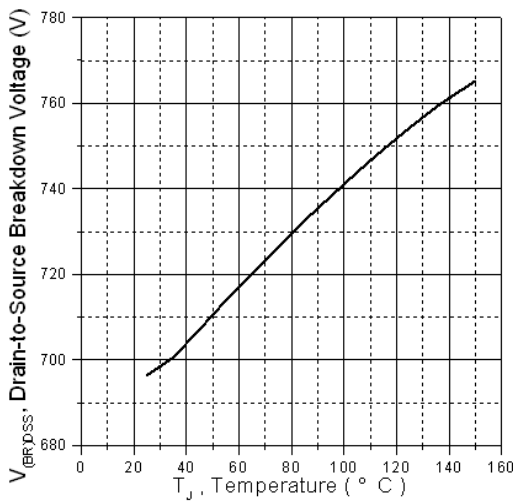
**Typical Electrical and Thermal Characteristics**



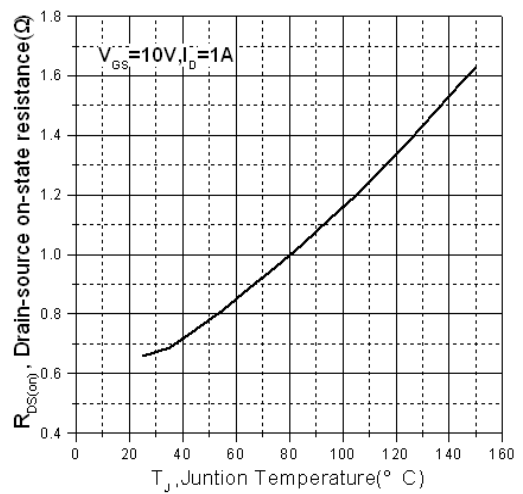
**Figure 1. Typical Output Characteristics**



**Figure 2. Gate to Source Cut-off Voltage**

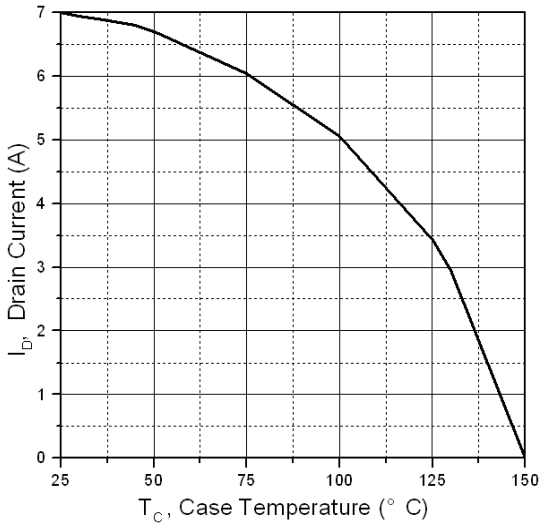


**Figure 3. Drain-to-Source Breakdown Voltage Vs. Case Temperature**

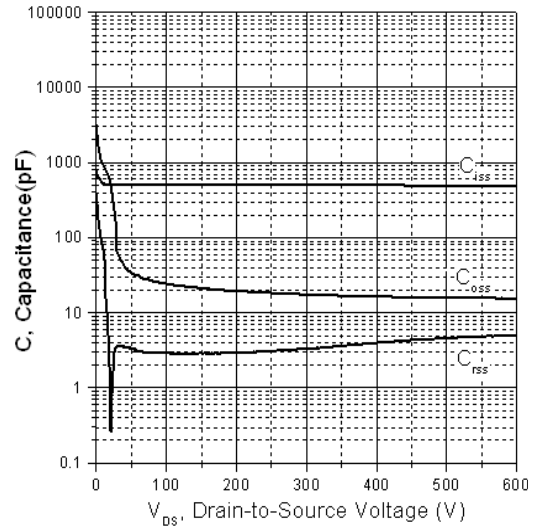


**Figure 4. Normalized On-Resistance Vs. Case Temperature**

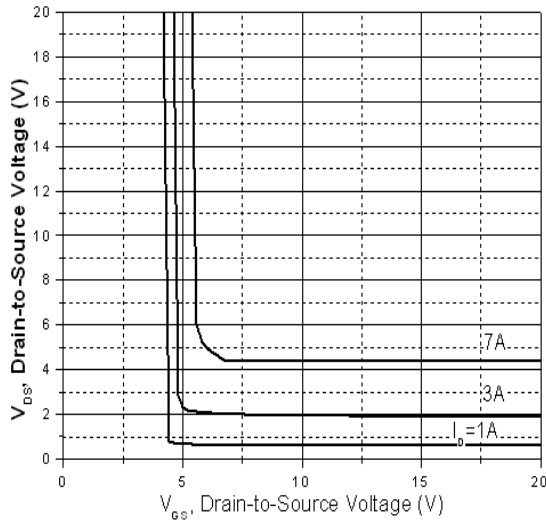
**Typical Electrical and Thermal Characteristics**



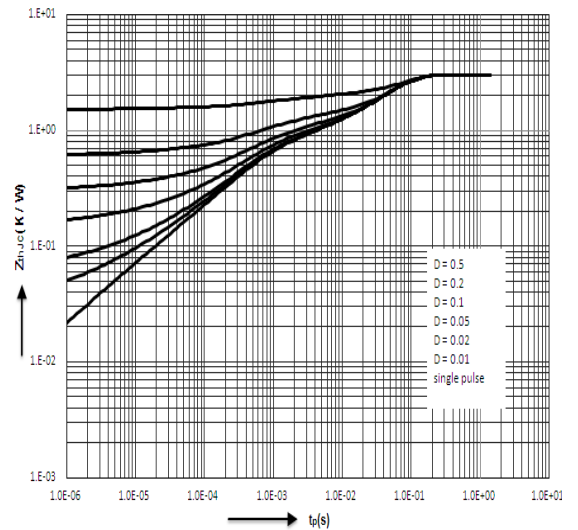
**Figure 5. Maximum Drain Current Vs. Case Temperature**



**Figure 6. Typical Capacitance Vs. Drain-to-Source Voltage**

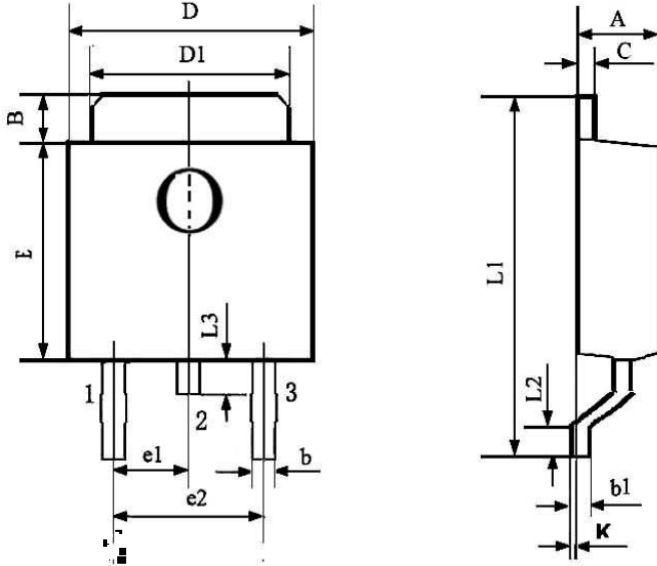


**Figure 7. Drain-to-Source Voltage Vs. Gate-to-Source Voltage**



**Figure 8. Maximum Effective Transient Thermal Impedance, Junction-to-Case**

**Package Outline Dimensions (TO-252/DPAK)**



Symbol	Dimensions In Millimeters			Dimensions In Inches		
	Min	Nom	Max	Min	Nom	Max
A	2.200	-	2.400	0.087	-	0.094
B	0.950	-	1.250	0.037	-	0.049
b	0.500	-	0.700	0.020	-	0.028
b1	0.450	-	0.550	0.018	-	0.022
C	0.450	-	0.550	0.018	-	0.022
D	6.450	-	6.750	0.254	-	0.266
D1	5.200	-	5.400	0.205	-	0.213
E	5.950	-	6.250	0.234	-	0.246
e1	2.240	-	2.340	0.088	-	0.092
e2	4.430	-	4.730	0.174	-	0.186
L1	9.450	-	9.950	0.372	-	0.392
L2	1.250	-	1.750	0.049	-	0.069
L3	0.600	-	0.900	0.024	-	0.035
K	0.000	-	0.100	0.000	-	0.004